Supplementary Information

Investigation of the role of in-plane stress behavior on ferroelectric properties of scaled-up hafnium zirconium oxide superlattices

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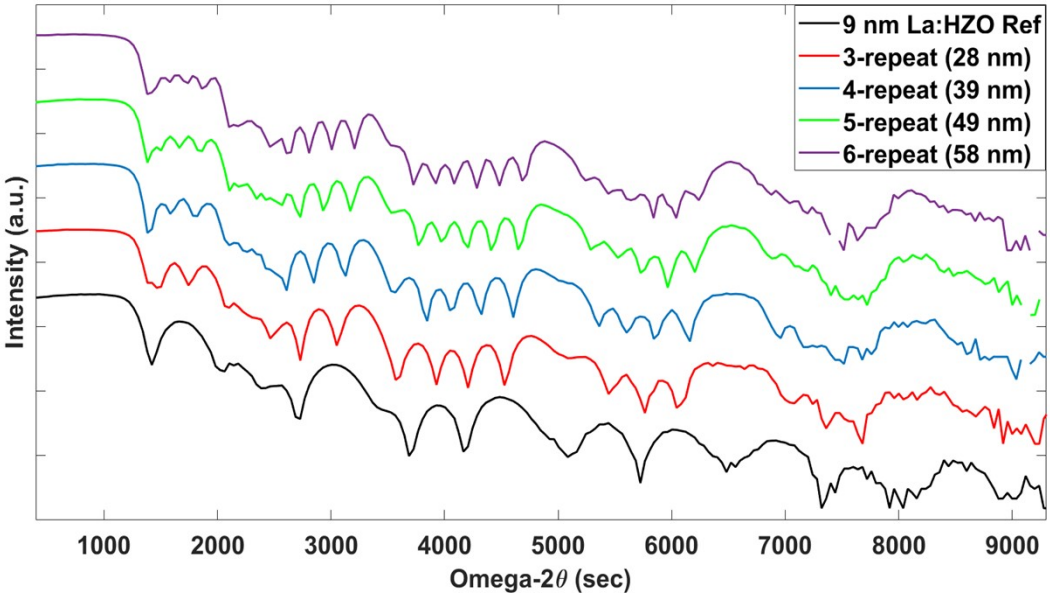

Figure S1: X-ray reflectivity (XRR) spectra of the single-layer reference and the superlattice stacks after the stacks have been subjected to PMA. The total thickness of the superlattices is indicated in brackets ().

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